FIG.1A

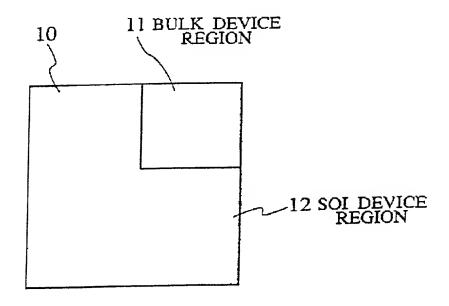
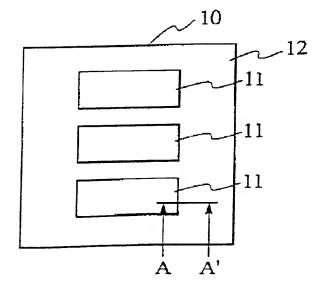
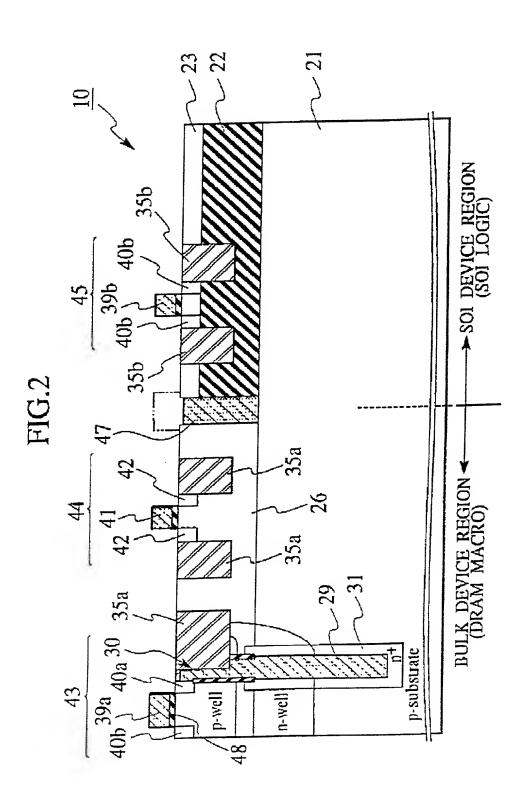
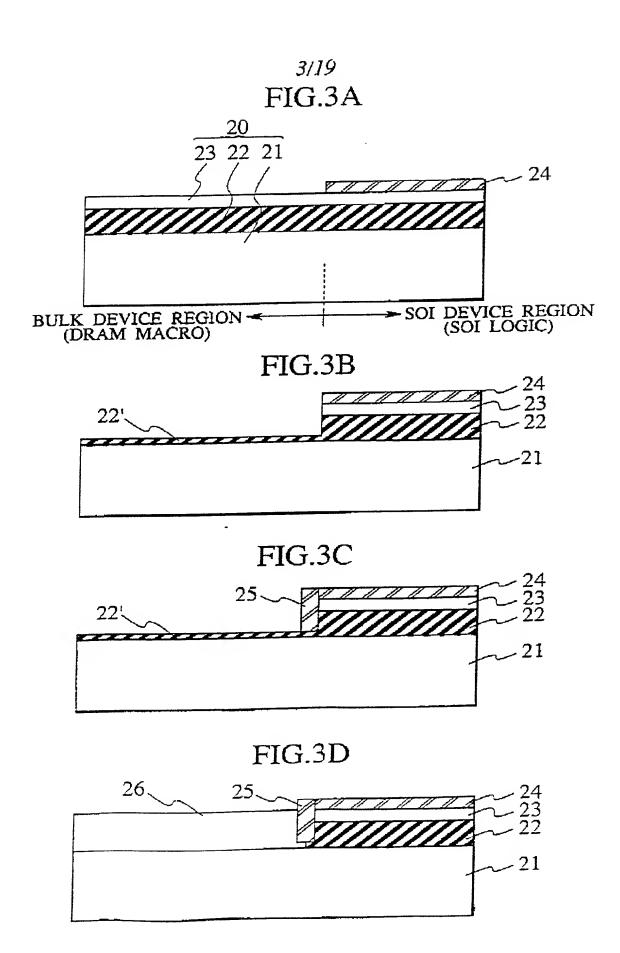


FIG.1B



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FIG.3E

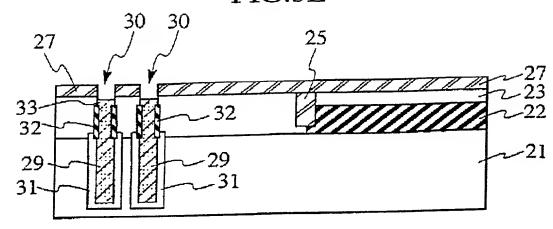


FIG.3F

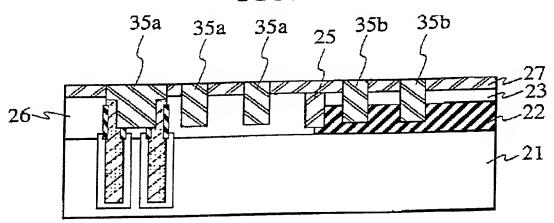
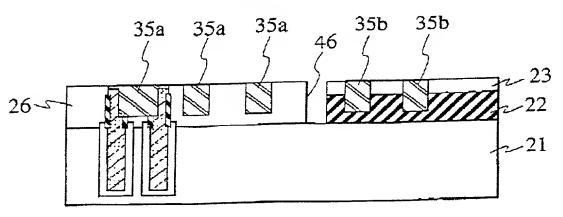


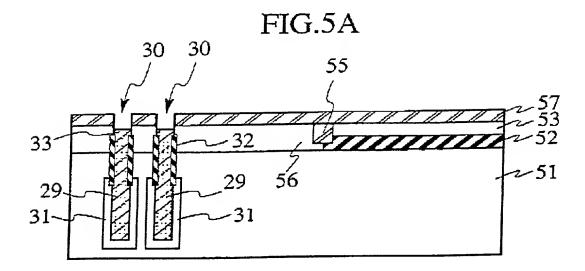
FIG.3G

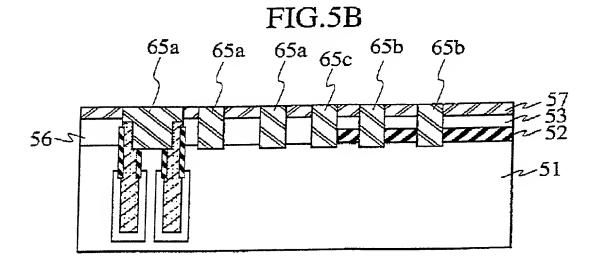


45 MOSFET ► SOI DEVICE REGION (SOI LOGIC) 65b 48 65b 56 BULK DEVICE REGION-(DRAM MACRO) p-substrate n-well p-well

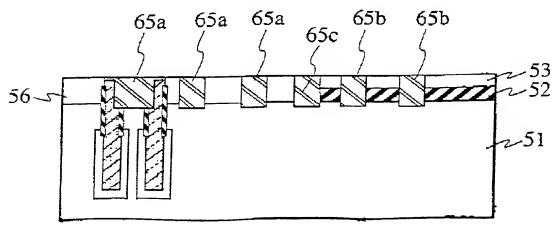
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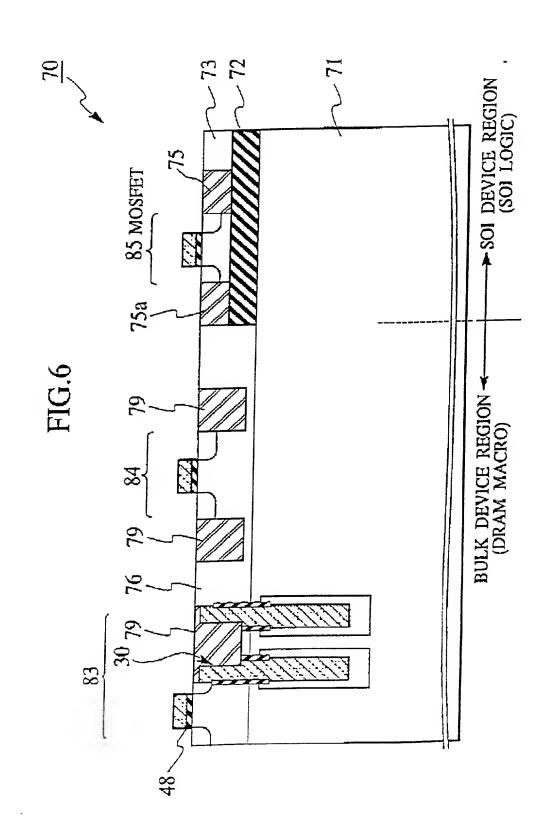




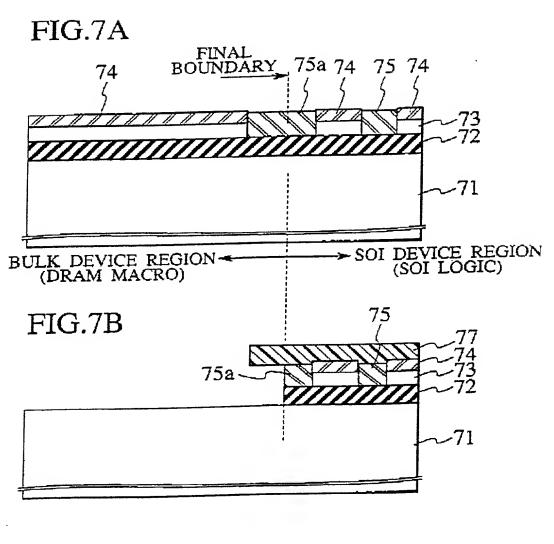


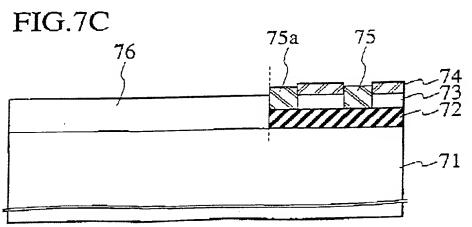


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FIG.7D

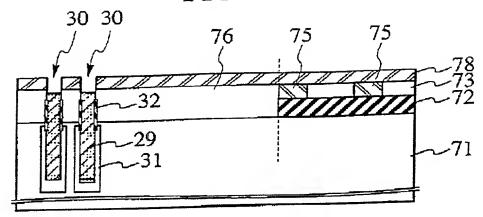


FIG.7E

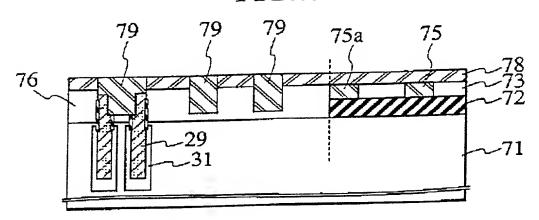
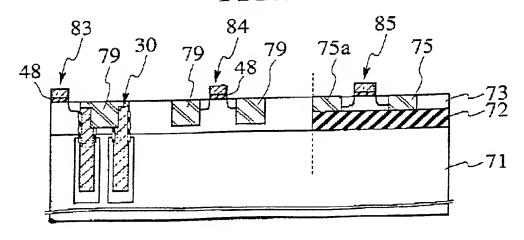
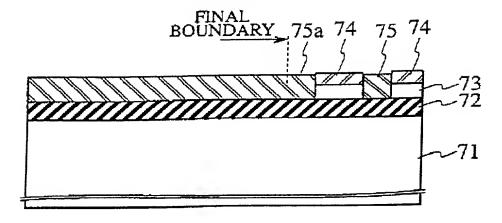


FIG.7F



# FIG.8A



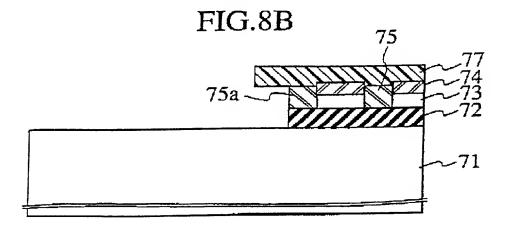
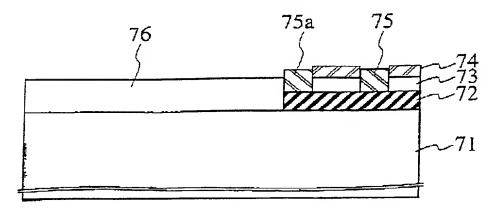
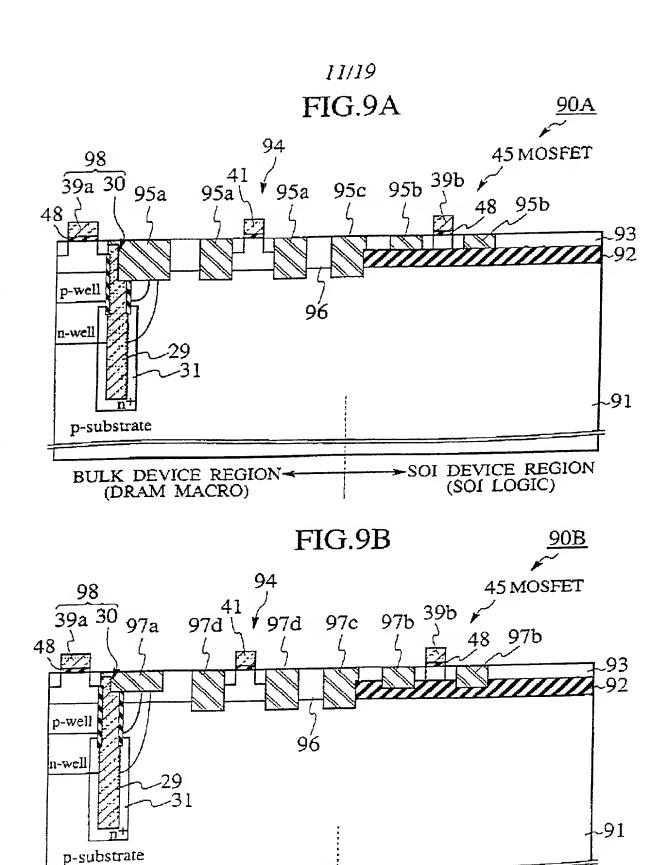


FIG.8C





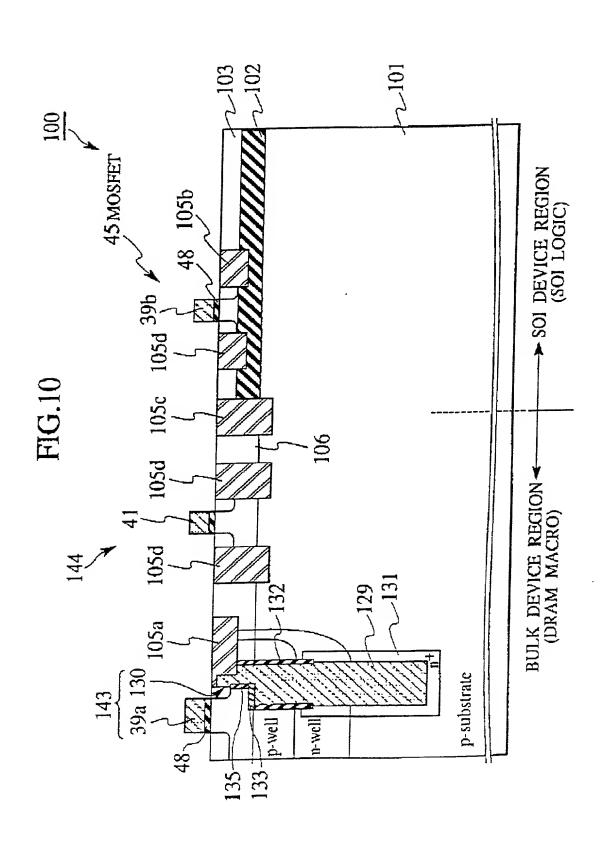
BULK DEVICE REGION-

(DRAM MACRO)

-SOI DEVICE REGION

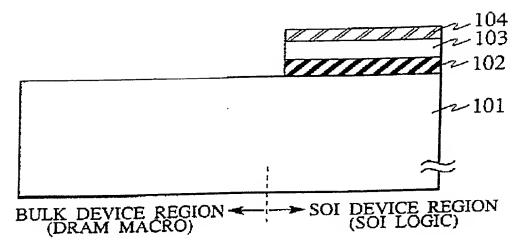
SOI LOGIC)

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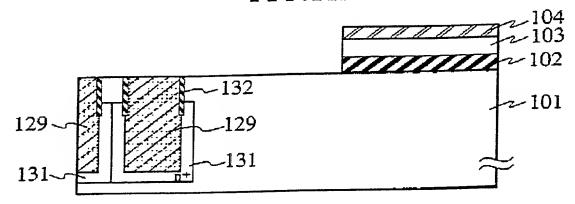


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## FIG.11A



## FIG.11B



# FIG.11C

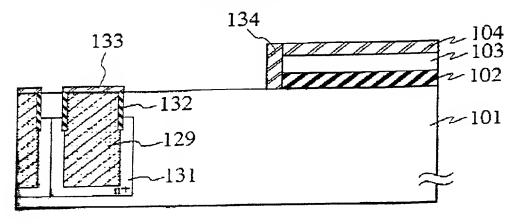


FIG.11D

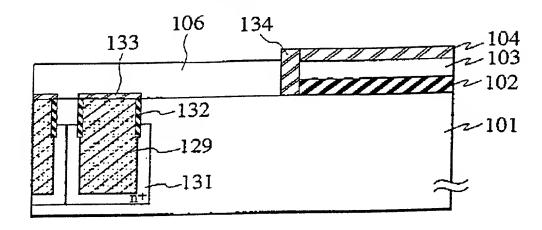


FIG.11E

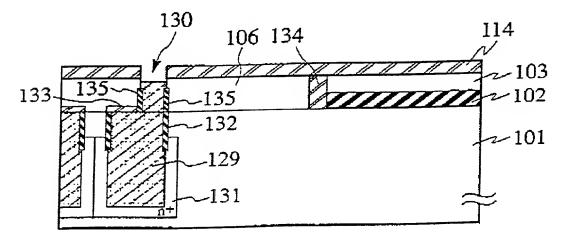
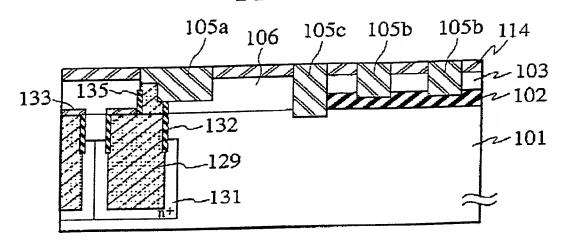
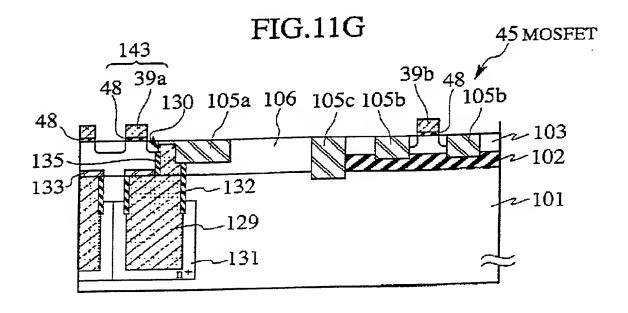
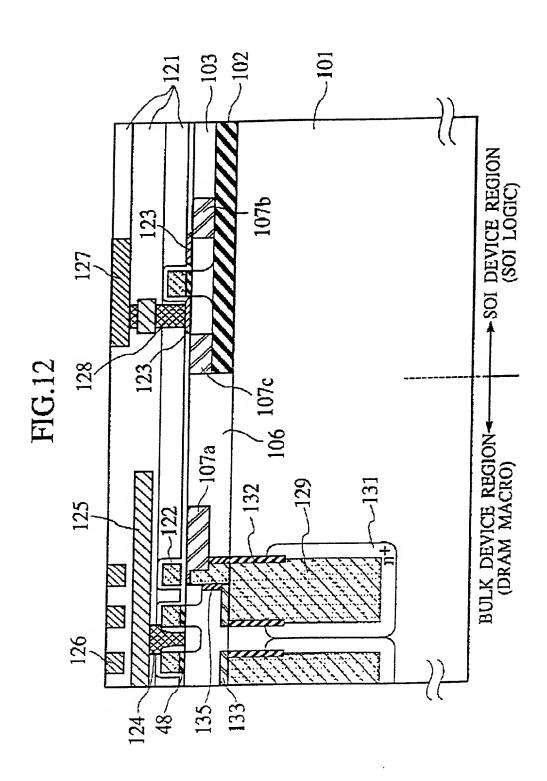


FIG.11F

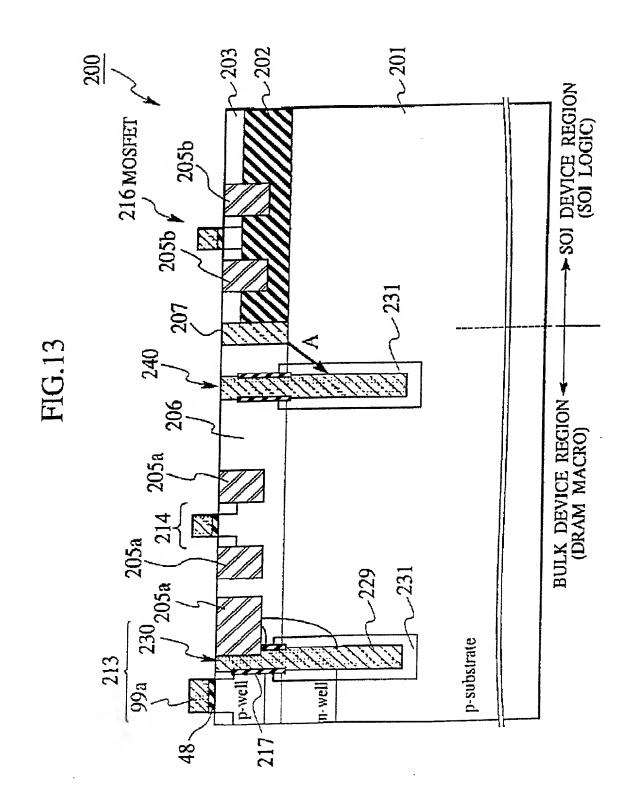




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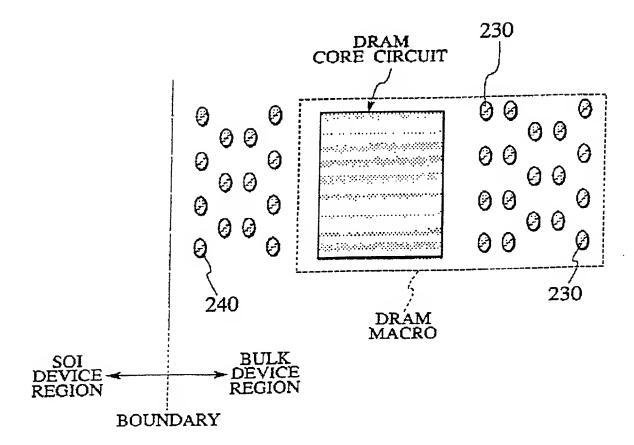


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FIG.15A

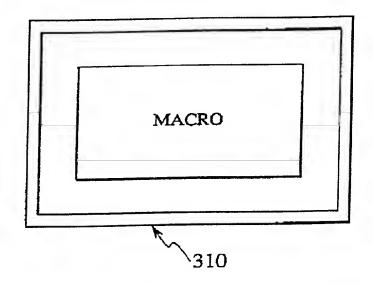


FIG.15B

